

# IGBT - Ultra Field Stop NGTB40N120L3WG

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Ultra Field Stop Trench construction, and provides superior performance in demanding switching applications, offering both low on–state voltage and minimal switching loss. The IGBT is well suited for motor driver applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

#### **Features**

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for Low V<sub>CEsat</sub>
- These are Pb-Free Devices

### **Typical Applications**

- Solar Inverter and UPS
- Industrial Switching
- Welding

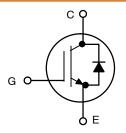
#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter Voltage	V <sub>CES</sub>	1200	V
Collector Current @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 100°C	Ic	160 40	A
Pulsed Collector Current, T <sub>pulse</sub> Limited by T <sub>Jmax</sub>	I <sub>CM</sub>	160	Α
Diode Forward Current @ $T_C = 25^{\circ}C$ @ $T_C = 100^{\circ}C$	I <sub>F</sub>	160 40	А
Diode Pulsed Current, T <sub>pulse</sub> Limited by T <sub>Jmax</sub>	I <sub>FM</sub>	160	Α
Gate-emitter Voltage Transient Gate-emitter Voltage ( $t_{pulse} = 5 \mu s, D < 0.10$ )	V <sub>GE</sub>	±20 ±30	V
Power Dissipation @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 100°C	P <sub>D</sub>	454 227	W
Operating Junction Temperature Range	T <sub>J</sub>	–55 to +175	°C
Storage Temperature Range	T <sub>stg</sub>	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1

40 A, 1200 V V<sub>CEsat</sub> = 1.55 V E<sub>off</sub> = 1.5 mJ





#### MARKING DIAGRAM



40N120L3 = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
G = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping
NGTB40N120L3WG	TO-247 (Pb-Free)	30 Units / Rail

## THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.33	°C/W
Thermal resistance junction-to-case, for Diode		0.61	°C/W
Thermal resistance junction-to-ambient		40	°C/W

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC						
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE}$ = 0 V, $I_C$ = 500 $\mu A$	V <sub>(BR)CES</sub>	1200	-	_	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A, T <sub>J</sub> = 175°C	V <sub>CEsat</sub>	- -	1.55 2.0	1.8 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$ , $I_C = 400 \mu A$	$V_{GE(th)}$	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V, T <sub>J =</sub> 175°C	I <sub>CES</sub>	- -	- 0.5	0.4	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	I <sub>GES</sub>	_	-	200	nA
DYNAMIC CHARACTERISTIC						•
Input capacitance		C <sub>ies</sub>	-	4912	-	pF
Output capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	-	140	-	1
Reverse transfer capacitance		C <sub>res</sub>	_	80	-	
Gate charge total		Qg	-	220	-	nC
Gate to emitter charge	$V_{CE}$ = 600 V, $I_{C}$ = 40 A, $V_{GE}$ = 15 V	Q <sub>ge</sub>	-	42	-	1
Gate to collector charge		Q <sub>gc</sub>	-	110	-	
SWITCHING CHARACTERISTIC, INDUCT	IVE LOAD					
Turn-on delay time		t <sub>d(on)</sub>	-	18	-	ns
Rise time		t <sub>r</sub>	-	30	-	
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	-	150	-	
Fall time	V <sub>CC</sub> = 600 V, I <sub>C</sub> = 40 A	t <sub>f</sub>	-	131	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 15 V$	E <sub>on</sub>	-	1.5	-	mJ
Turn-off switching loss		E <sub>off</sub>	-	1.5	-	
Total switching loss		E <sub>ts</sub>	-	3.0	-	1
Turn-on delay time		t <sub>d(on)</sub>	-	18	-	ns
Rise time		t <sub>r</sub>	-	31	-	
Turn-off delay time	T <sub>J</sub> = 175°C	t <sub>d(off)</sub>	-	156	-	
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 40 \text{ A}$ $R_{g} = 10 \Omega$	t <sub>f</sub>	-	220	-	
Turn–on switching loss	$V_{GE} = 15 \text{ V}$	E <sub>on</sub>	-	2.0	-	mJ
Turn–off switching loss		E <sub>off</sub>	-	2.3	-	
Total switching loss		E <sub>ts</sub>	-	4.3	-	1
DIODE CHARACTERISTICS						
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 40 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 40 A T <sub>J =</sub> 175°C	V <sub>F</sub>	_ _	3.0 2.8	3.4	V
Reverse recovery time		t <sub>rr</sub>	_	86	-	ns
Reverse recovery charge	T <sub>J</sub> = 25°C	Q <sub>rr</sub>	_	0.56	-	μс
Reverse recovery current	$I_F = 40  A$ , $V_R = 600  V$	I <sub>rrm</sub>	-	12	-	Α
Diode peak rate of fall of reverse recovery	di <sub>F</sub> /dt = 500 A/μs	dl <sub>rrm</sub> /dt	_	-210	_	A/μs

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
DIODE CHARACTERISTICS						
Reverse recovery time		t <sub>rr</sub>	_	136	-	ns
Reverse recovery charge	T <sub>J</sub> = 125°C	$Q_{rr}$	-	1.47	-	μς
Reverse recovery current	I <sub>F</sub> = 40 Å, V <sub>R</sub> = 600 V di <sub>F</sub> /dt = 500 Å/us	I <sub>rrm</sub>	-	20	-	Α
Diode peak rate of fall of reverse recovery current during tb		dI <sub>rrm</sub> /dt	-	-212	ı	A/μs

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

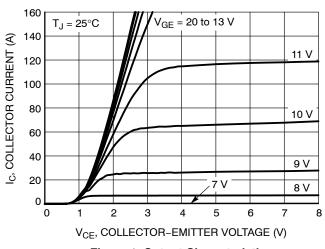


Figure 1. Output Characteristics

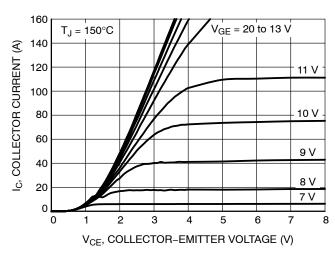


Figure 2. Output Characteristics

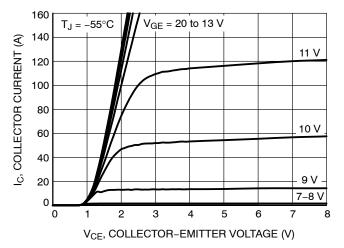


Figure 3. Output Characteristics

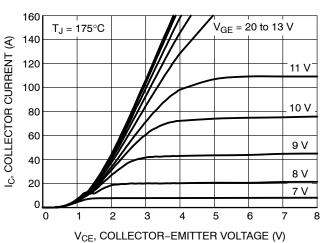


Figure 4. Output Characteristics

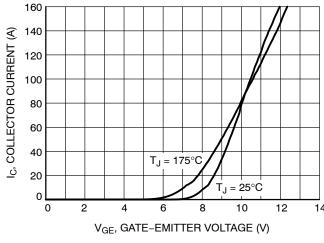


Figure 5. Typical Transfer Characteristics

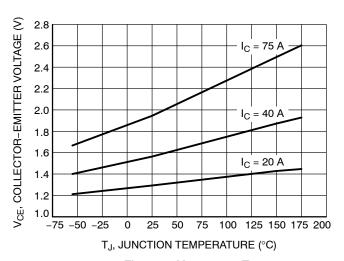


Figure 6. V<sub>CE(sat)</sub> vs. T<sub>J</sub>

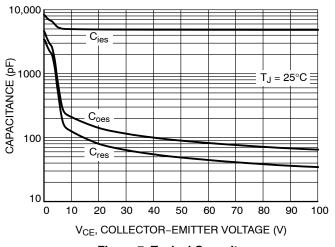


Figure 7. Typical Capacitance

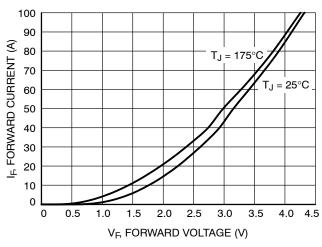


Figure 8. Diode Forward Characteristics

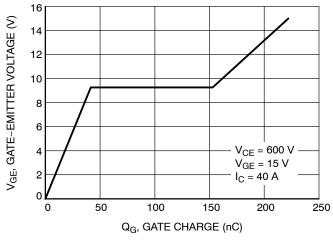


Figure 9. Typical Gate Charge

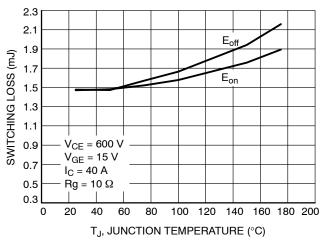


Figure 10. Switching Loss vs. Temperature

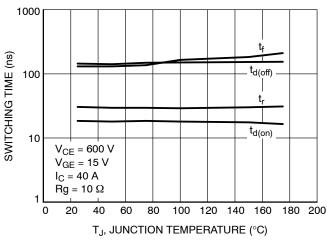


Figure 11. Switching Loss vs. Temperature

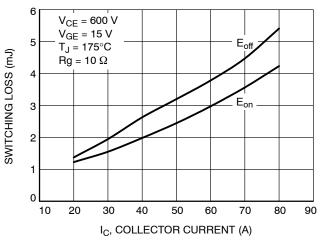


Figure 12. Switching Loss vs. I<sub>C</sub>

#### **TYPICAL CHARACTERISTICS**

SWITCHING LOSS (mJ)

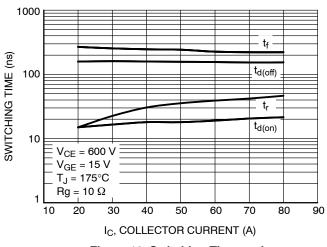


Figure 13. Switching Time vs. I<sub>C</sub>

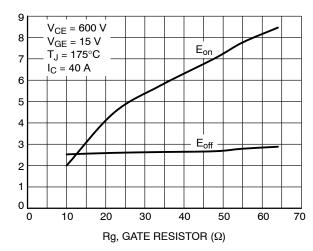


Figure 14. Switching Loss vs. R<sub>G</sub>

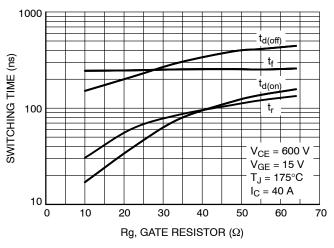


Figure 15. Switching Time vs. R<sub>G</sub>

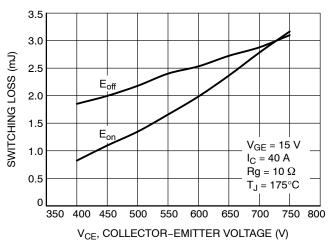


Figure 16. Switching Loss vs. V<sub>CE</sub>

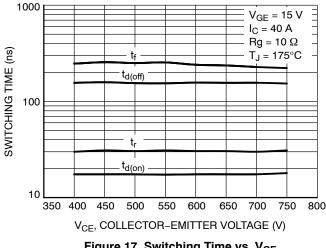


Figure 17. Switching Time vs. V<sub>CE</sub>

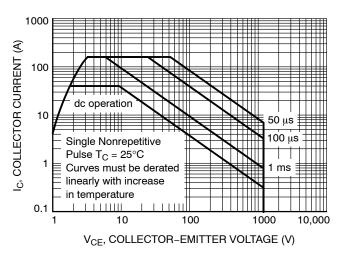
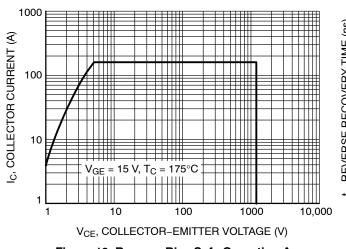


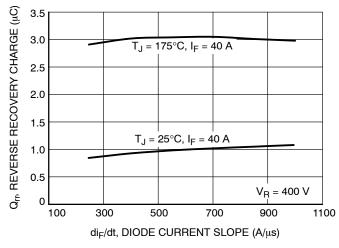
Figure 18. Safe Operating Area



350 REVERSE RECOVERY TIME (ns)  $V_{R} = 400 \text{ V}$ 300  $T_J = 175^{\circ}C, I_F = 40 \text{ Å}$ 250 200 150 100  $T_J = 25^{\circ}C$ ,  $I_F = 40 \text{ A}$ 50 بئ 100 300 500 700 900 1100  $di_{\text{F}}/dt$ , DIODE CURRENT SLOPE (A/ $\mu$ s)

Figure 19. Reverse Bias Safe Operating Area

Figure 20.  $t_{rr}$  vs.  $di_F/dt$ 



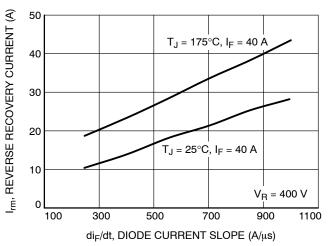


Figure 21. Q<sub>rr</sub> vs. di<sub>F</sub>/dt

Figure 22.  $I_{rm}$  vs.  $di_F/dt$ 

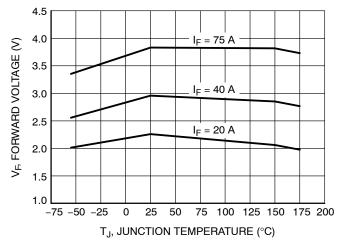


Figure 23.  $V_F$  vs.  $T_J$ 

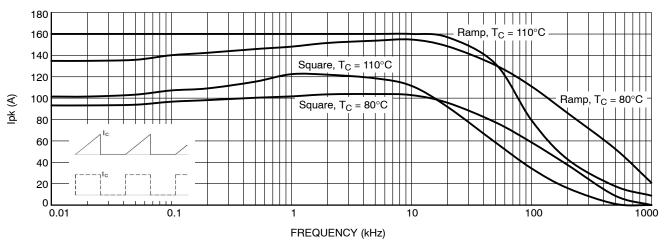


Figure 24. Collector Current vs. Switching Frequency

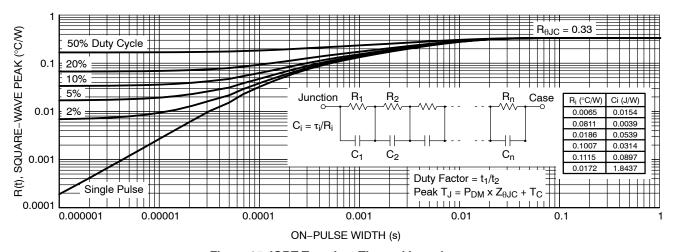


Figure 25. IGBT Transient Thermal Impedance

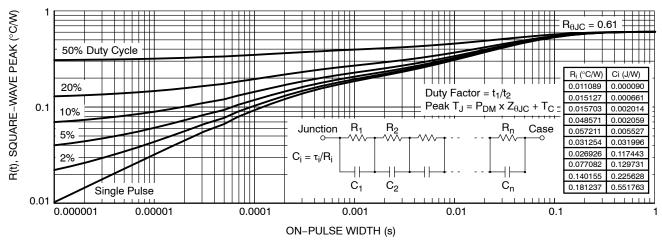


Figure 26. Diode Transient Thermal Impedance

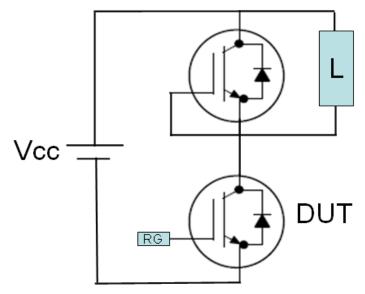


Figure 27. Test Circuit for Switching Characteristics

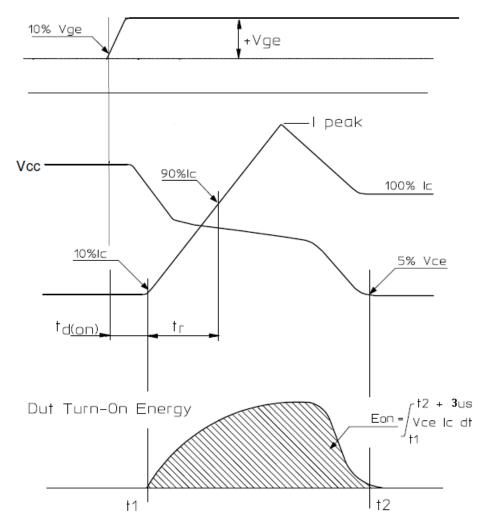


Figure 28. Definition of Turn On Waveform

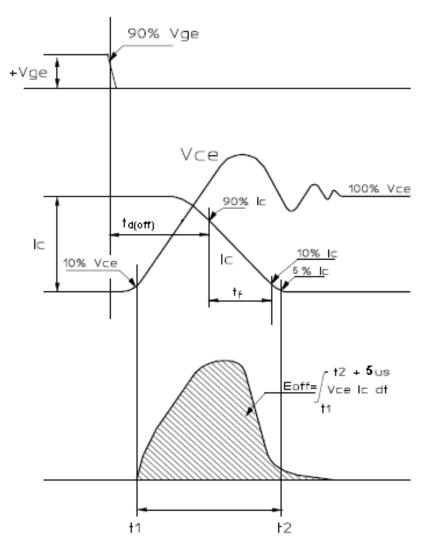
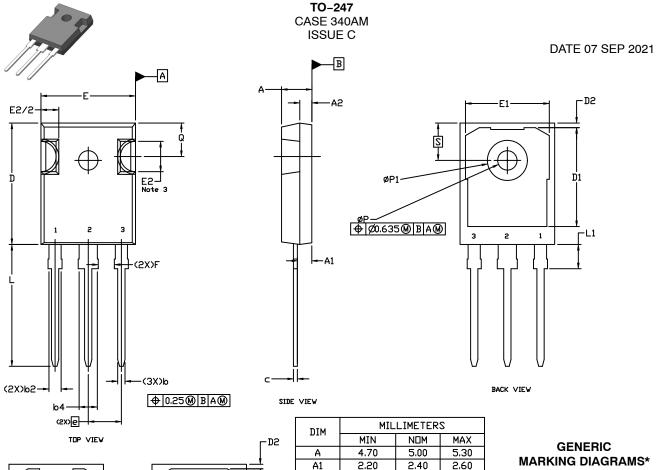


Figure 29. Definition of Turn Off Waveform





A2

b b2

b4

D

D1

D2

Ε

E1

E2

F

L1

P

P1

Q

S

1.07

1.65

2.60

0.45

20.80

16.30

0.75

15.50

13.80

4.32

2.655

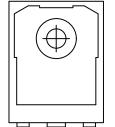
19.80

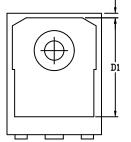
3.81

3.55

6.60

5.40





NOTE 4 HEATSINK SHAPES

#### NOTES:

- 1. DIMENSIONING AND TOLERANCE AS PER ASME Y14.5M, 2009.
- 2. ALL DIMENSION ARE IN MILLIMETERS.
- SLOT REQUIRED, NOTCH MAY BE ROUNDED. 3.
- OPTIONAL BACK SIDE HEATSINK SHAPE.
- DIMENSIONS ARE EXCLUSIVE OF BURRS AND MOLD FLASH.
  DIMENSIONS D AND E ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
- 6. DIMENSIONS AT TO BE MEASURED IN THE REGION DEFINED BY L1.
- 7. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

#### **MARKING DIAGRAMS\*** 2.20 2.40 2.60 1.80 2.00 2.20 1.20

1.33

2.35

3.40

0.75

21.34

16.25

5.49

20.80

4.35

3.65

6.20

2.12

3.12

0.60

21.00

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16.00

4.90

20.00

4.20

3.60

6.00

6.15 BSC

5.45 BSC





XXXX = Specific Device Code = Assembly Location

Υ = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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